

ATS

Auto Test System

Control solution for automating TLP test systems

The **ATS** Auto Test System automates component-level TLP testing, delivering the current pulse sequentially to individual pins on the device under test.

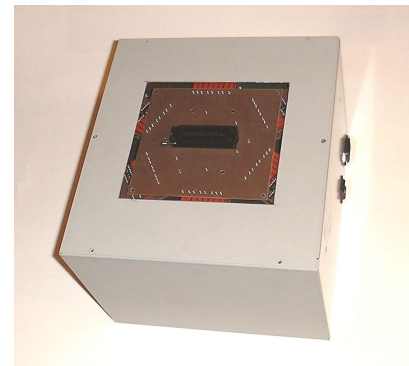
The **ATS** replaces the time-consuming task of manually attaching clips or leads to the DUT pins in turn.

Benefits of the **ATS** include:

- Reduce component handling
- Minimize operator error
- Increase test efficiency
- Solid electrical connection to DUT
- Enhance repeatability of TLP testing

System

The **ATS** standard system supports testing up to 48 pins. The system is easily expandable to support multiple power supplies.



Quick Swap

Innovative interface board features quick-swap capability, enabling the user to switch IC socket styles, from DIP to SOIC to PLCC. The interface board is also extendable to probe card solutions.

Programmable

Pin test sequence can be stored for re-use during the IC development process.